

Notice of References Cited	Application/Control No. 09/839,794	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,779,017	08-2004	Lamberton et al.	709/203
	C	US-6,901,445	05-2005	McCanne et al.	709/225
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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